

FCC ID:	A3LSMS928JPN
Date:	10/30/2023
Test Procedure:	KDB 680106 D01 v04

Load	E Measurements (V/m)	10% Battery Distance from probe (cm)	50% Battery Distance from probe (cm)	90% Battery Distance from probe (cm)	Limit (V/m)
		15	15	15	
	A (Bottom)	0.398	0.398	0.381	614.00
	B (Right)	0.456	0.381	0.381	614.00
Phone	C (Top)	0.398	0.391	0.381	614.00
Phone	D (Left)	0.398	0.389	0.391	614.00
	E (Front)	0.536	0.398	0.390	614.00
	F (Back)	0.662	0.381	0.418	614.00

Table 1. E-field Measurement by battery level (phone load)

Load	E Measurements (V/m)	Distance from probe (cm) 15	Limit (V/m)
Watch	F (Back)	1.212	614.00
Earbuds	F (Back)	0.433	614.00

Table 2. E-field Measurement (non-phone loads)

H Measurements (A/m)	10% Battery Distance from probe (cm) 15	50% Battery Distance from probe (cm) 15	90% Battery Distance from probe (cm) 15	Limit (A/m)
A (Bottom)	0.149	0.154	0.150	1.63
B (Right)	0.154	0.152	0.149	1.63
C (Top)	0.154	0.148	0.150	1.63
D (Left)	0.145	0.150	0.145	1.63
E (Front)	0.145	0.148	0.154	1.63
F (Back)	0.159	0.149	0.150	1.63
	(A/m) A (Bottom) B (Right) C (Top) D (Left) E (Front) F (Back)	H Measurements (A/m) Distance from probe (cm)   A (Bottom) 0.149   B (Right) 0.154   C (Top) 0.154   D (Left) 0.145   E (Front) 0.145   F (Back) 0.159	Distance from probe (A/m) Distance from probe (cm) Distance from probe   1 15 15   A (Bottom) 0.149 0.154   B (Right) 0.154 0.152   C (Top) 0.154 0.148   D (Left) 0.145 0.150   E (Front) 0.145 0.148   F (Back) 0.159 0.149	Distance (A/m) Distance from probe (cm) Distance from probe (cm) Distance from probe (cm)   15 15 15   A (Bottom) 0.149 0.154 0.150   B (Right) 0.154 0.152 0.149   C (Top) 0.154 0.150 0.145   D (Left) 0.145 0.148 0.154

Table 3. H-field Measurement by battery level (phone load)

Load	H Measurements (A/m)	Distance from probe (cm) 15	Limit (A/m)
Watch	F (Back)	0.204	1.63
Earbuds	F (Back)	0.154	1.63

Table 4. H-field Measurement (non-phone loads)

FCC ID: A3LSMS928JPN	element RF EXPOSURE E-/H-FIELD TEST REPORT		SAMSUNG	Approved by: Managing Director
Filename:	Test Dates:	EUT Type:		Dage 1 of 2
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## Notes:

- 1. The right and left edge are determined with the EUT screen facing the user.
- 2. H-Field Measurements were found to be noise floor.

## **Description of Test Setup**

- o Testing was performed with a calibrated field probe.
- o Measurement was performed on each side of the EUT as indicated in Table 1 and Table 3.
- Testing was performed at the distances and different battery levels as indicated in Table 1 and Table 3.
- Measurement procedure was performed per FCC Guidance.

## Test Equipment

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Narda	EHP-200AC	Electronic & Magnetic Field Probe	10/21/2022	Biennial	10/21/2024	170WX60209
Table 6. Test Equipment						

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